

Supporting Information

Optimizing the gradient of electric field distribution and inhibiting charge injection in multilayer dielectric films for high capacitive performance

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Experimental

Materials

P(VDF-HFP) powders were purchased from Poly K. $\text{Ni}(\text{NO}_3)_2 \cdot 6\text{H}_2\text{O}$ (99 %) powders, 1,4-benzenedicarboxylic acid (1,4- H_2BDC 99 %), N, N-dimethylformamide (DMF, 99.5 %) and acetonitrile ($\text{C}_2\text{H}_3\text{N}$, 99.9 %) were purchased from Shanghai Maclean Biochemical Co.

Characterization

The crystal structure of the composite materials was obtained by X-Ray Diffraction (XRD) on a D8 Advance X-ray diffractometer. The dielectric properties of all samples were measured by an LCR (TH 2838A, Changzhou Tonghui Electronics Co., Ltd., China) in the range of 10^3 to 10^6 Hz. The polarization-electric field (P - E) loops were measured by the Premier II Ferroelectric test system (Poly K). The fast discharge tests were performed using a CF-003 test system (Instruments Technology, China).

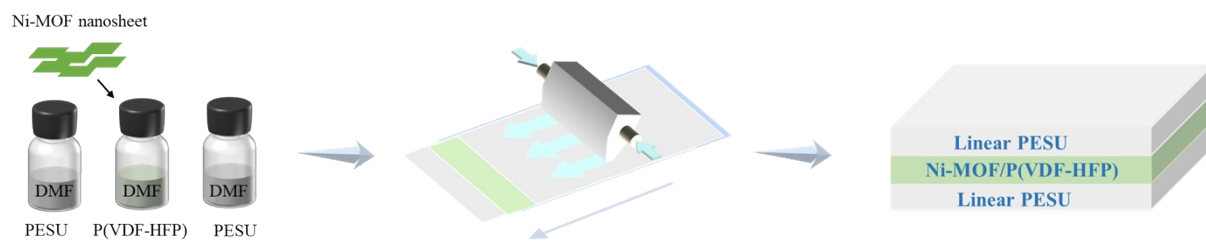


Figure S1. The preparation process of multilayer composite films.

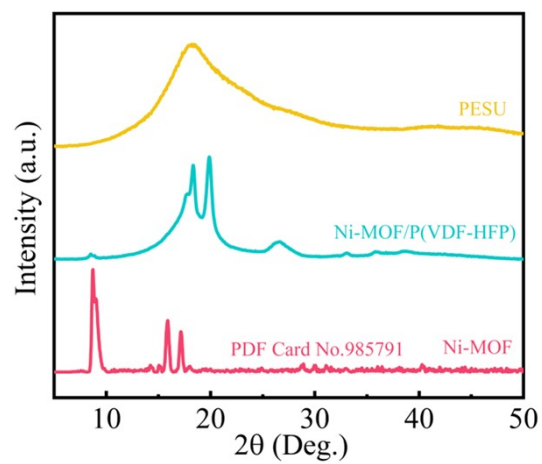


Figure S2. The XRD image of P(VDF-HFP), Ni-MOF/ P(VDF-HFP), and PESU.

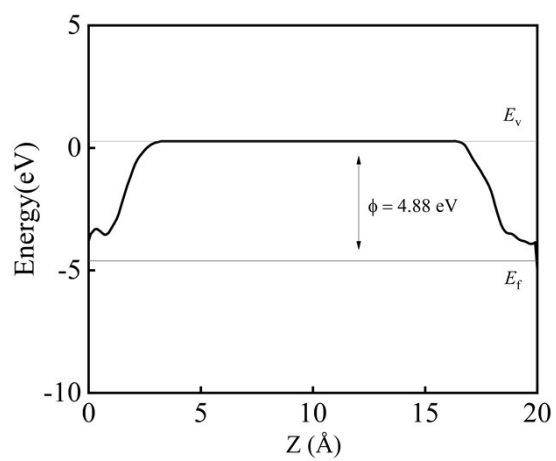


Figure S3. The work function of PESU.

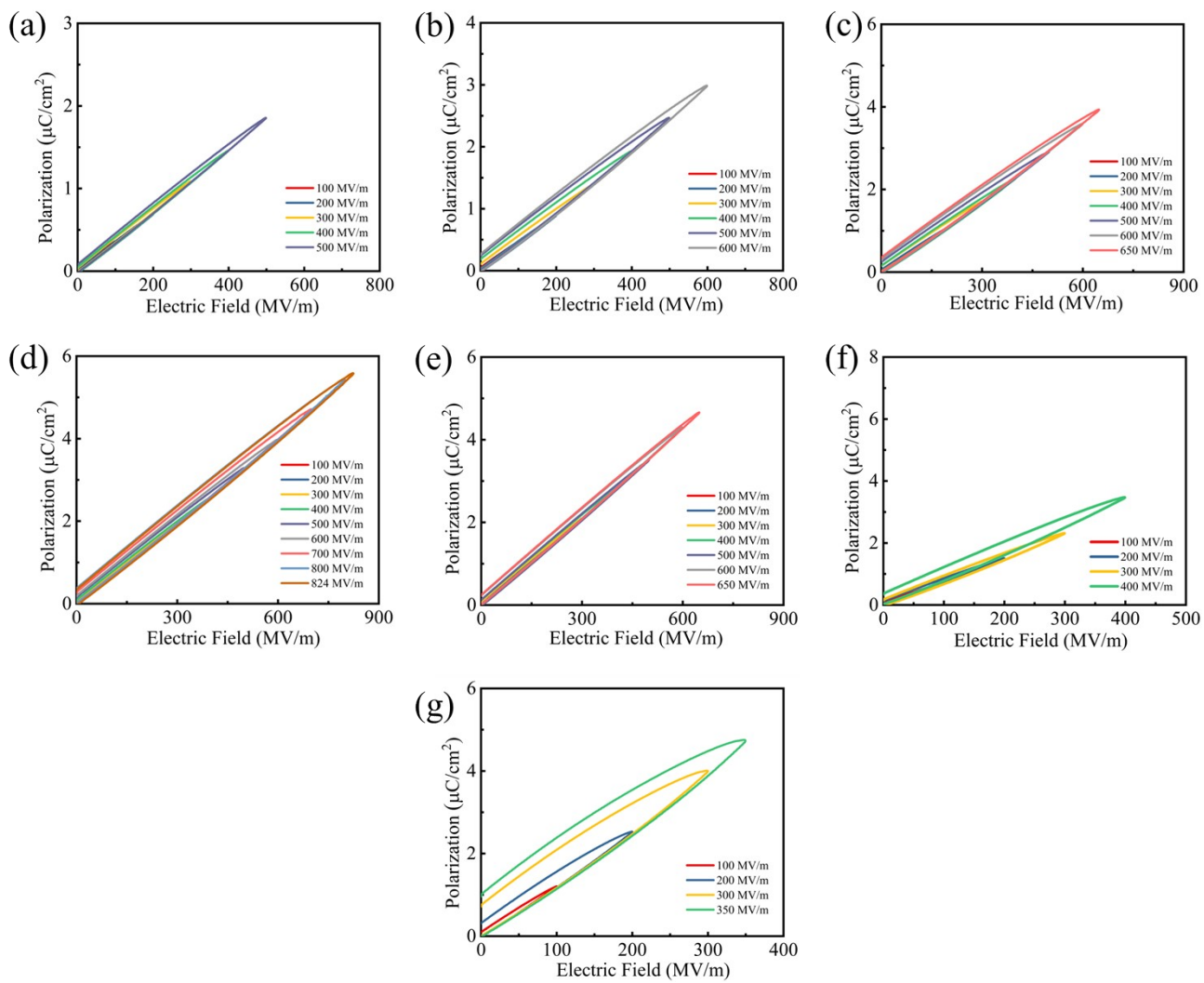


Figure S4. The P - E loops of PESU, PP-0, PP-1, PP-2, PP-3, PP-4, and P(VDF-HFP) under different electric fields.